

Search Notes**Application/Control No.**

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Examiner

EDMUND H. LEE

**Applicant(s)/Patent under
Reexamination**

IWASAKI ET AL.

Art Unit

1791

SEARCHED

Class	Subclass	Date	Examiner
updated		5/27/2008	EHL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
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